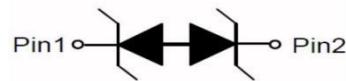


## 1. General Description

The MESD5V0UF11B is designed to protect voltage sensitive components from damage or latch-up due to ESD. Excellent clamping capability, low leakage, and fast response time provide best in class protection on designs that are exposed to ESD for board level. Because of its small size and bi-directional design, it is ideal for use in cellular phones, MP3 players, and portable applications that require audio line protection.



## DFN1006-2L (Bottom View)



## Circuit Diagram

## 2. Specification Features

- Small Body Outline Dimensions: nom 0.039" x 0.024" (1.0x0.6 mm)
- Low Body Height: nom 0.019" (0.5 mm)
- Low Clamping Voltage
- Reverse Working (Stand-off) Voltage: 5.0 V
- Low Leakage
- Response Time is Typically < 1 ns
- ESD Rating of Class 3 (> 16 kV) per Human Body Model
- IEC61000-4-2 Level 4 ESD Protection
- This is a Pb-Free Device

### 3. Application

- USB 3.0 and Universal Flash Storage (UFS) data lines
- Cellular handsets and accessories
- Portable electronics
- Communication systems
- Computers and peripherals

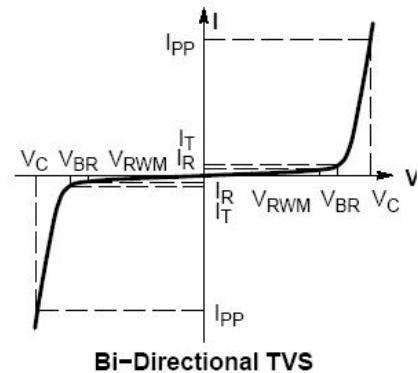
## 4. Maximum Ratings

Rating	Symbol	Value	Unit
IEC 61000-4-2 (ESD) Contact		±15	kV
ESD Voltage	Per Human Body Model	16	kV
	Per Machine Model	400	V
Peak Power Per 8 x 20µs Waveform	P <sub>PK</sub>	100	W
Total Power Dissipation on FR-5① Board @ TA = 25°C	P <sub>D</sub>	100	mW
Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C
Lead Solder Temperature - Maximum (10 Second Duration)	T <sub>L</sub>	260	°C

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## 5. Characteristics

Symbol	Parameter
$I_{PP}$	Maximum Reverse Peak Pulse Current
$V_C$	Clamping Voltage @ IPP
$V_{RWM}$	Working Peak Reverse Voltage
$I_R$	Maximum Reverse Leakage Current @ VRWM
$I_T$	Test Current
$V_{BR}$	Breakdown Voltage @ $I_T$
$P_{PK}$	Peak Power Dissipation
$C$	Capacitance @ $VR = 0$ and freq.=1 MHz



Mark	$V_{RWM}$ (V)	$I_R$ ( $\mu$ A) @ $V_{RWM}$			$V_{BR}$ (V) @ $I_T$			$I_T$ (mA)	Max. $V_C$ (V) @ $I_{PP}^2=4A$	C(Pf)	
		Typ.	Max.	Min.	Type	Max.	Type			Type	Max
M8	5	0.05	1	6.0	8.3	9	1	1	25	0.4	0.55

Note: Surge current wave form per figure 3.

## 6. Typical Characteristics

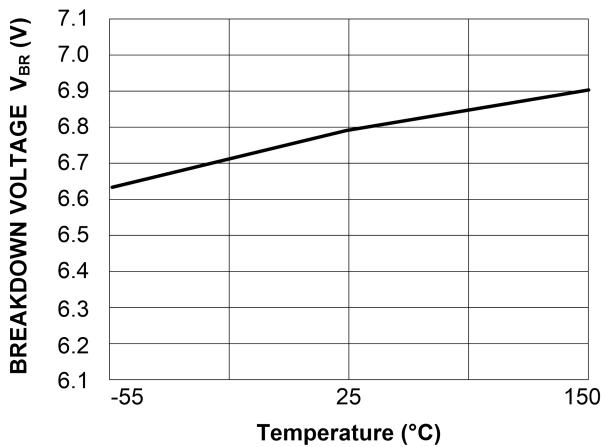


Figure 1: Typical Breakdown Voltage versus Temperature

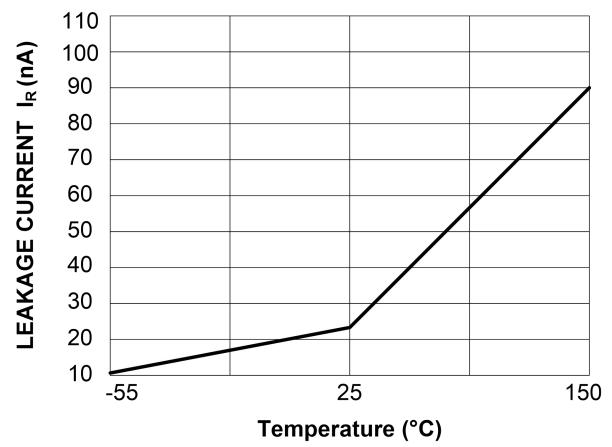


Figure 2: Typical Leakage Current versus Temperature



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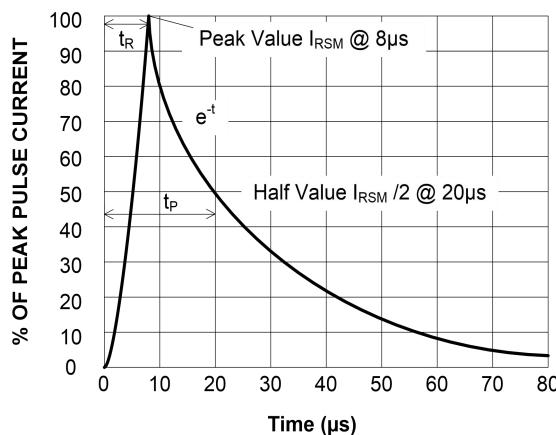
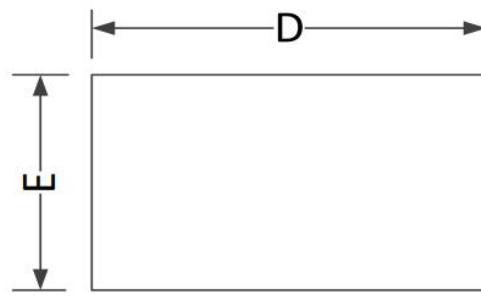


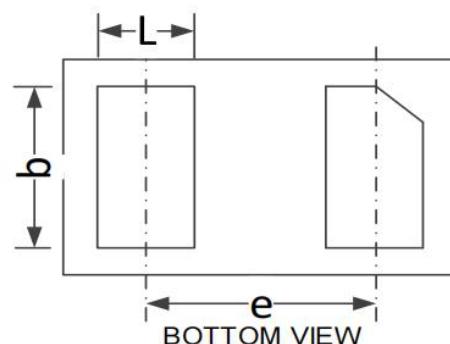
Figure 3: 8/20μs Pulse Wave Form

## 7. Package Outline Dimensions

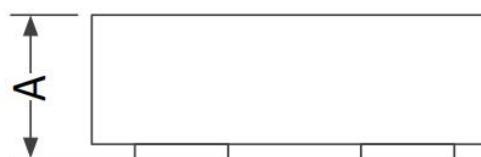
Device Marking	Device	Package	Reel size	Tape width	Quantity
M8	MESD5V0UF11B	DFN1006-2L	7inch	8mm	12K



TOP VIEW



BOTTOM VIEW



SIDE VIEW

COMMON DIMENSION (MM)			
PKG	DFN1006		
REF.	MIN.	NOM.	MAX.
A	0.40		0.55
b	0.45	0.50	0.55
D	0.95	1.00	1.05
e	0.65BSC		
A	0.55	0.60	0.65
L	0.20	0.25	0.30



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